Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/666,806	AYDIN, ATAKAN
Examiner	Art Unit

Christopher M. Babic

1637

	SEARCHED				
Class	Subclass	Date	Examiner		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEAI (INCLUDING S	RCH NOTE SEARCH S	TRATEGY)
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